



Deposited via The University of Leeds.

White Rose Research Online URL for this paper:

<https://eprints.whiterose.ac.uk/id/eprint/130180/>

Version: Accepted Version

Conference or Workshop Item:

Barimah, E, Ziarko, M, Bamiedakis, N et al. (Accepted: 2018) Femtosecond-Pulsed Laser Deposition of Erbium-Doped Glass Nanoparticles in Polymer Layers for Hybrid Optical Waveguide Amplifiers. In: AVS 65th International Symposium and Exhibition, 21-26 Oct 2018, Long Beach, CA, USA. (Unpublished)

Reuse

Items deposited in White Rose Research Online are protected by copyright, with all rights reserved unless indicated otherwise. They may be downloaded and/or printed for private study, or other acts as permitted by national copyright laws. The publisher or other rights holders may allow further reproduction and re-use of the full text version. This is indicated by the licence information on the White Rose Research Online record for the item.

Takedown

If you consider content in White Rose Research Online to be in breach of UK law, please notify us by emailing eprints@whiterose.ac.uk including the URL of the record and the reason for the withdrawal request.

Session: Femtosecond-Pulsed Laser Deposition of Erbium-Doped Glass Nanoparticles
EM12 in Polymer Layers for Hybrid Optical Waveguide Amplifiers.

Abstract #
748

Author(s)

Eric Barimah; University of Leeds, UK, United Kingdom of Great Britain and Northern Ireland

Marcin Ziarko; University of Cambridge, United Kingdom of Great Britain and Northern Ireland

Nikolaos Bamiedakis; University of Cambridge, United Kingdom of Great Britain and Northern Ireland

Ian White; University of Cambridge, United Kingdom of Great Britain and Northern Ireland

Richard Penty; University of Cambridge, United Kingdom of Great Britain and Northern Ireland

Gin Jose; University of Leeds, UK

Presenter
X

Correspond
X

Abstract: (SUPPLEMENTAL DOCUMENT was submitted with the abstract)

Tellurium oxide (TeO₂) based glasses are widely used in many applications such as fibre optic, waveguide devices and Raman gain, and are now being considered for use in optical waveguide amplifiers. These materials exhibit excellent transmission in the visible and near IR wavelength range (up to 2.0 μm), low phonon energy, and high rare-earth solubility. Siloxane polymer materials on the other hand, have remarkable thermal, mechanical and optical properties and allow the fabrication of low-loss optical waveguides directly on printed circuit boards. In recent years, various low-cost optical backplanes have been demonstrated using this technology. However, all polymer optical circuits used in such applications are currently passive, requiring therefore amplification of the data signals in the electrical domain to extend the transmission distance beyond their attenuation limit. The combination of the TeO₂ and siloxane technologies can enable the formation of low-cost optical waveguide amplifiers that can be deployed in board-level communications. However, there are significant technical challenges associated with the integration of these two dissimilar materials mainly due to the difference in their thermal expansion coefficients.

In this paper therefore, we propose a new approach for incorporating erbium (Er³⁺)-doped tellurium-oxide glass nanoparticles into siloxane polymer thin films using femtosecond pulsed laser deposition (fs-PLD). Erbium-doped sodium zinc tellurite (Er-TZN) nanoparticles (NPs) are embedded into siloxane polymer films spin-coated on silica substrates using fs-PLD at low temperatures (100 °C) and under two different pulse energies. The surface morphology, and the compositional and structural characteristics of the samples fabricated are evaluated using scanning and transmission electron microscopy (SEM and TEM), TEM- energy-dispersive X-ray spectrometry, X-ray diffraction (XRD), and Raman spectroscopy. Additionally, photoluminescence (PL) and lifetime measurements are carried out at 1534 nm at room temperature under a 980 nm laser diode excitation. The SEM results show that average particle size of the Er-TZN NPs incorporated into polymer layer decreases with decreasing fs-pulse laser energy, while the PL measurements reveal a full-width at half-maximum (FWHM) of about 39 nm. The respective FWHM value obtained from the bulk glass is 51 nm. The obtained luminescence lifetime of the samples is in the range 3.52 to 4.18 ms, which is slightly lower than the value obtained from the bulk glass target of 4.37 ms.